

Fourth edition  
2020-07

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# **Cards and security devices for personal identification — Test methods —**

## **Part 6: Contactless proximity objects**

*Cartes et dispositifs de sécurité pour l'identification personnelle —  
Méthodes d'essai —*

*Partie 6: Objets sans contact de proximité*



Reference number  
ISO/IEC 10373-6:2020(E)

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Published in Switzerland

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## Foreword

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This document was prepared by Joint Technical Committee ISO/IEC JTC 1, *Information technology, SC 17, Cards and security devices for personal identification*.

This fourth edition cancels and replaces the third edition (ISO/IEC 10373-6:2016), which has been technically revised. It also incorporates the Amendment ISO/IEC 10373-6:2016/Amd.3:2018.

The main changes compared to the previous edition are as follows:

- enhancement of test methods for PCD load modulation reception and PICC transmission including introduction of Active Reference PICC and PICC amplitude and phase drift analysis tool;
- introduction of PICC Type A Frame Delay Time (FDT) determination method;
- extension of frame with error correction test methods.

A list of all the parts in the ISO/IEC 10373 series can be found on the ISO website.

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